FCC ID: 2AU4M-HR70

Portable device
According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.
According to KDB447498 D01 General RF Exposure Guidance V06
The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:
[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]·[√f(GHZ)] ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BLE:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
BLE(1M)	2.402	-2.17	0.61	-2±1	-1	0.79	<5	0.24622	3.00	YES
	2.440	-2.39	0.58	-2±1	-1	0.79	<5	0.24816	3.00	YES
	2.480	-2.66	0.54	-2±1	-1	0.79	<5	0.25018	3.00	YES
BLE(2M)	2.402	-2.09	0.62	-2±1	-1	0.79	<5	0.24622	3.00	YES
	2.440	-2.29	0.59	-2±1	-1	0.79	<5	0.24816	3.00	YES
	2.480	-2.59	0.55	-2±1	-1	0.79	<5	0.25018	3.00	YES

ANT:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
ANT+ 1M	2.457	-2.36	0.58	-2±1	-1	0.79	<5	0.24902	3.00	YES
ANT+ 2M	2.457	-2.31	0.59	-2±1	-1	0.79	<5	0.24902	3.00	YES

Note: This product does not support the requirements under BT/ANT transmission simultaneous

Conclusion:

For the max result : 0.25018 ≤ 3.0 for 1g SAR, SAR is not required.

Signature: **Date:** 2023-02-27

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